

TECHNICAL SPECIFICATION



**Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection – Glossary –
Part 4-4: Piezoelectric materials – **Materials** Single crystal wafers for surface acoustic wave (SAW) devices**

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

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Part 4-4: Piezoelectric materials – ~~Materials~~ Single crystal wafers for surface acoustic wave (SAW) devices

FOREWORD

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- the required support cannot be obtained for the publication of an International Standard, despite repeated efforts, or
- the subject is still under technical development or where, for any other reason, there is the future but no immediate possibility of an agreement on an International Standard.

Technical specifications are subject to review within three years of publication to decide whether they can be transformed into International Standards.

IEC TS 61944-4-4, which is a technical specification, has been prepared by IEC technical committee 49: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection.

This third edition of IEC 61994-4-4 cancels and replaces the second edition published in 2010. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) the new terms and definitions given in IEC 62276:2016 have been taken into account;
- b) the general title has been changed according to the change in the title of TC 49 in 2009.
- c) the part title has been changed according to the title of IEC 62276:2016.

The text of this technical specification is based on the following documents:

Enquiry draft	Report on voting
49/1283/DTS	49/1287/RVC

Full information on the voting for the approval of this technical specification can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 61994 series, published under the general title *Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection – Glossary*, can be found on the IEC website.

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PIEZOELECTRIC, DIELECTRIC AND ELECTROSTATIC DEVICES AND ASSOCIATED MATERIALS FOR FREQUENCY CONTROL, SELECTION AND DETECTION – GLOSSARY –

Part 4-4: Piezoelectric materials –~~Materials~~ Single crystal wafers for surface acoustic wave (SAW) devices

1 Scope

This part of IEC 61994 ~~specifies~~ gives the terms and definition for single crystal wafers ~~applied~~ for surface acoustic wave (SAW) devices representing the state of the art, ~~which are intended for use in the standards and documents of IEC technical committee 49.~~

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

~~ISO 4287, Geometrical Product Specifications (GPS) – Surface texture: Profile method – Terms, definitions and surface texture parameters~~

There are no normative references in this document.

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Part 4-4: Piezoelectric materials – Single crystal wafers for surface acoustic wave (SAW) devices**



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**Part 4-4: Piezoelectric materials – Single crystal wafers
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1 Scope

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